

Technical Information

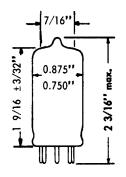
12AT7WA

RELIABLE MINIATURE DOUBLE TRIODE

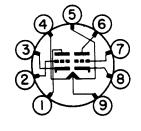
MECHANICAL DATA

ENVELOPE	T6½Glass
OUTLINE	JEDEC (6-2)
BASE	9 Pin Miniature
BASING	9A
MOUNTING POSI	TIONAny

PHYSICAL DIMENSIONS



BASING



BOTTOM VIEW

FERMINAL	CONNECTIONS:

Pin i	Plate, Unit #2
Pin 2	Grid, Unit #2

Pin 3 Cathode, Unit #2

Pin 4 Heater

Pin 5 Heater

Pin 6 Plate, Unit #1

Pin 7 Grid, Unit #1

Pin 8 Cathode, Unit #1

Pin 9 Heater Center—Tap

The 12AT7WA is a heater-cathode type, high-mu double triode of miniature construction, suitable for use in amplifier, mixer, oscillator, multivibrator and computer circuits. The high amplification factor (60) makes it ideal for audio amplifier service where a gain of 40 is easily realized. The low plate resistance plus the ample peak plate current make this type ideal for pulse amplifier and low power servo amplifier service. This type is controlled for cathode interface and is designed for dependable operation under conditions of shock and vibration encountered in mobile, aircraft and missile applications. A heater center tap is provided to permit operation at 12.6 volts or parallel operation at 6.3 volts.

MECHANICAL RATINGS:

Maximum Impact Acceleration (Shock—Test—Note 3)	630	G
Maximum Vibrational Acceleration (96 hour Fatigue Test-Note 4)	2.5	G
Maximum Bulb Temperature	165	°C
Altitude 60	.000	ft.

ELECTRICAL DATA

Ratings and Normal Opera	tion_	MIL -E Symb	ol .	Test Limit or Design Minimum	Normal Test Conditions	Normal Operation	Test Limit or Design Maximum	MIL-E-1 Units
		<i>.</i>	Series	11.4	12.6	12.6	13.9	٧
Heater Voltag	e	Ef:	parallel	5.7	6.3	6.3	6.9	V
Plate Voltage		Eb:		•••	250	250	330	Vdc
Grid Voltage		Ecl:		-55	0	0	0	Vdc
Plate Dissipa (per Plate)	tion	Pp/p	:			2.5	2.5	W
Heater—Catho Voltage	ode	Ehk:			•••	•••	± 100	¥
Grid Resist—	Fixed Bias	Rg/g	:	•••		•••	0.25	Meg.
ance	Cathod Bias	le Rg∕g	:			•••	0.5	Meg.
					Tests			
Plate Current (per plate)	(1)	lb/p:		7	•••	10	14	mAdc
Cathode Resi (per cathode)	stance	Rk/k	:	•••	200	200	•••	ohms
Transconduct	ance	Sm/p	:	4500		5500	6500	<i>µ</i> mhos
Amplification	Factor	Mu∕p	:	50		60	70	
Heater Curren (Series)	it	lf:		142	•••	150	158	mA
Plate Current Cut—off (Ec1: —20 Vdc)		lb/b:		•••	•••	•••	100	μAdc
Plate Current difference bet sections		Δ 1b:		•••	•••	•••	3.2	mAdc



Ratings and Normal Operation	MIL-E-1 Symbol	Test Limit or Design Minimum	Normal Test Conditions	Normal Operation	Test Limit or Design <u>Maximum</u>	MIL_E_1 Units
			Tests			
Vibration(parallel) f=40 cps; G=10	Ep:	•••	•••		100	mVac
Capacitance (no shield)	Cgp:	1.3	•••	1.6	1.9	µия
Capacitance (no shield)	Cin:	2.0		2.5	3.0	μμt
Capacitance (no shield) Section 1	Cout:	0.20	•••	0.45	0.70	μμε
Capacitance (no shield) Section 2	Cout:	0.16	•••	0.38	0.60	μμŧ
Capacitance (no shield)	Срр:	0.15	•••	0.24	0.33	μμf
Capacitance (no shield)	Chk:	2.1	•••	2.8	3.50	μμ

SPECIAL TESTS AND RATINGS TO INSURE RELIABILITY.

Randomly selected statistical samples are subjected to the following tests:

Shock Test –	630 G. 42° hammer angle in Navy high impact shock machine. Sample subjected to twenty
	impact accelerations, five impact accelerations in each of four different positions.

Fatigue Test — 2.5G. Sample subjected to vibrational acceleration of 2.5G for 96 hours (32 hours in each of three positions). The sinusoidal vibration is applied at a fixed frequency between 25 and 60 cycles per second.

Glass Strain – A sample is subjected to a forty eight hour holding period at room temperature. The sample is immersed in water at 97–100 °C for 15 seconds and immediately immersed in water at not

more than 5 °C. The sample is then dried at room temperature for 48 hours and inspected for evidence of air leaks.

Heater-Cycling A sample is subjected to 2000 on-off heater cycles at the following conditions. Ef = 7.5V Life Test- (heaters in parallel); Ehk = +135 Vdc and other elements floating. At the conclusion of this test the tubes will not show open heater or cathode circuits and meet a maximum lhk leakage limit of 15 μ Adc.

Stability Life Test— Sample is operated for two and twenty hours to evaluate initial electrical stability

 $(\Delta_{+} \text{Sm} \le 10\%).$

9/1/60 :

Survival Rate Sample is operated one hundred hours to evaluate inoperatives and early electrical stability.

Life Test —

Intermittent 1000 hours. Sample is operated with minimum Envelope Temperature of 165 °C. Life Test –

Interface 500 hours. Sample is operated with Ef = 6.9 V (heaters in parallel) other electrodes dis— Life Test— connected. (Interface resistance < 50 ohms).



Altitude - Sample is subjected to a pressure of 55 ± 5 mmHg to evaluate flashover or corona at the pins of the tube.

APPLICATION NOTES

CAUTION — — To Electron Equipment Design Engineers. Special attention should be given to the temperature which the tubes are to be operated. Reliability will be seriously impaired if maximum bulb temperature is exceeded. The life expectancy may be reduced if conditions other than those specified for life test are imposed on the tube and will be reduced appreciably if maximum ratings are exceeded. Both reliability and performance will be jeopardized if filament voltage ratings are exceeded. Life and reliability of performance are closely related to the degree that regulation of the heater voltage is maintained at its center rated value.

ACCEPTANCE CRITERIA

The following tests shall be performed:

For the purpose of inspection, use applicable reliable paragraphs of Specification MIL-E-1.

For miscellaneous requirements, see 3.6.

Par. No.	Test (See Note 1)	Conditions	AQL (Percent	Inspection Level or	Symbol			LIMI (See No				Units
			Defective)	Code		Min	Lal	Bogie	Ual	Max	Ald	<u> </u>
GENER	RAL											
3.1	Qualification	Required for JAN marking										
3.6	Performance											
QUALI	FICATION TESTS (see n	ote 3)										
	Cathode	Coated unipotential										
3.4.3	Base Connections	Outline E9-1										
4.9.20.3	Variable frequency vibration (1)	Ec= -3 Vdc; Rp= 2,000; Rk= 0 (see note 4)		• • •	Ep		***		•••	100		mVo
MEASU	REMENT ACCEPTANCE	TESTS, PART 1 (see no	ote 5)									
4.10.8	Heater Current				lf .		146	150	154		9	mA
4.10.8	Heater Current		0.4	ll II	lf .	142				158		mA
4.10.15	Heater—Cathode Leakage	Ehk=+100 Vdc Ehk=—100 Vdc (see note 6)	0.4	li li	ihk ihk					7 7		μAd μAd
4.10.6.1	Total Grid Current	Rg=0.5 Meg (see note 6)	0.4	ll II	lc	0	•••	•••		-0.7		μAd
4.10.4.1	Plate Current (1)	(see note 6)			lb		8.5	10.0	11.5	•••	3.4	mA
4.10.4.1	Plate Current (1)	(See note 6)	0.4	- 11	1b	7.0		•••		14.0		mAd
4.10.4.1	Plate Current (2)	Ec=-20 Vdc; Rp=0.1 Meg; Rk=0; Ck=0 (see note 6)	0.4		l ib		•••		•••	100	•••	μAd
4.10.9	Transconductance(1)	Ck=1,000 µf (see note 6)	•••		Sm	•••	5000	5500	6000		1000	<i>µ</i> mh
4.10.9	Transconductance(1)	Ck = 1000 μ f (see note 6)	0.4	11	Sm	4500				6500		μmh
4.7.5	Continuity and Shorts		0.4	11								
4.9.1	Mechanical— production tests	Outline 6—7										



Par. No.	Test (See Note 1)	Conditions	AQL (Percent	Inspection Level or	Symbol			LIMI [*] (See Not				Units
			Defective)	Code	1	Min	Lal	Bogie	Ual	Max	Ald	1
MEASURI	EMENTS ACCEPTANCE	TESTS, PART 2										
4.8	Insulation of elec — trodes	(see note 6) E (g—all)=—100 Vdc E (p—all)=—300 Vdc	2.5	L6	[R R	500 500			•••			Meg Meg
4.10.4.1	Plate Current (1) (difference between sections)		2.5	1	lь	•••				3.2		mAd
4.10.4.1	Plate Current (3)	Ec=_7.0 Vdc Rp=0.1 Meg Rk/k=0(see note 6)	2.5	t .	lb	5						μAdo
4.10.9	Transconductance (2)	Ef=11.4 V Ck=1000 μf (see note 6)	2.5	1	Δ_{Ef^Sm}				•••	15		%
4.10.6.2	Grid Emission	Ef=15.0 V Ec=—20 Vdc; Rg/g=0.5 Meg Rk=0; Ck=0 (see notes 6 and 7)	2.5	i	lc	0			•	-1.5		μAdo
4.10.3.1	Radio—frequency noise (other than shot—effect noise)	Ecal = 15 mVac Rk = 100; Ck = 0.2 μf (see notes 4 and 8)	2.5	I								
4.10.3.4	Noise and micro— phonics (for re— liable receiving tubes)	Ef=12.6 Vdc; Ebb=300 Vdc; Ecal=100 mVac; Rk=200; Rp=10,000; grid grounded; Ck=1,000 µf (see notes 4 and 9)	2.5	l								
	Pulse cathode current	Ef=12.6 V Eb=250 Vdc; Ec=-30 Vdc; Rk=1.0 (see notes 6 and 10)	2.5	Code H	ik	280			•••	•••		ma
4.10.11.1	Amplification factor	(see note 6)	6.5	լ6	Mυ	50			•••	70		
4.10.14	Direct Interelec— trode capacitance	No shield No shield No shield; section 1 No shield; section 2 No shield No shield	6.5	Code E	Cgp Cin Cout Cout Cpp Chk	1.30 2.00 0.20 0.16 0.15 2.10				1.90 3.00 0.70 0.60 0.33 3.50		144 144 144 144 144
4.9.12.1	Low-pressure voltage breakdown	Pressure=55±5mmHg; voltage=500 Vac	6.5	(See Note 11								
4.9.19.1	Low-frequency vibration (2)	Ec=-3 Vdc; Rp=2,000; Rk=0; Ck=0; G=10; F=40 cps (see note 4)	6.5	Code I	Ер					100		mVac
DEGRAI	DATION RATE ACCEPT	ANCE TESTS, (see note 1	2)									
4.9.20.5	Shock test	Hammer angle=42°; Ehk=+100 Vdc (see note 13)				•••				•••		
4.9.20.6	Fatigue test	G=2.5; fixed frequency; F=25 min. 60 max.	6.5	(See Note 11		•••			•••			•••
	Post shock and fatigue test end	Vibration (2) Heater-cathode leakage	•••	•••	Ep ILI.	•••		•••	•••	150		mVac
Ì	points	Ehk=+100 Vdc Ehk=+100 Vdc	•••	•••	lhk lhk	•••			•••	20 20		μAdo
		Transconductance (1) Grld Current			Sm	3800	•••		•••	-1.5		μmho μAdo



Par. No.	Test (See Note 1)	Conditions	AQL (Percent	Inspection Level or				LIMIT (See No				
			Defective)	Code		Min	Lal	Bogie	Ual	Max	Ald	Units
4.9.6.1	Miniature—tube base— strain				•••	•••		•••				•••
4.9.6.3	Glass strain (for receiving tubes)		2.5					•••				
4.11.7	Heater—cycling life test	Ef=7.5V; heaters in parallel Ehk=+135Vdc (see note 14)							•••	•••		•••
4.11.4	Life-test end points	Heater cathode leakage Ehk=+100 Vdc Ehk=—100 Vdc			ihk ihk				•••	15 15		μAdc μAdc
	Stability life test	Ehk=+135 Vdc Rg/g=0.5 meg. TA=room (see note 15)	1.0	Code I								
4.11.4	Life—test end points (stability) (2 and 20 hours)	Change in transcon— ductance (1) of in— dividual tubes		•••	$\Delta_{_{f f}}$ Sm	•••				10		%
4.11.3.1(b)	Survival —rate life test	Stability life test conditions or equivalent (see notes 16 and 17)		#1								•
4.11.4	Life—test end points (survival rate) (100 hours)	Continuity and shorts Transconductance(1)	0.65 1.0	•••	Sm	3800						 μmhos
4.11.5	Intermittent life— test operation	Stability life test conditions; T (envelope)= 165°C min (see notes 18 and 19)			•••	•••					•••	

					Allowable Defects per characteristic			LIMITS		
Par. No.	Test	Conditions	AQL (Percent Defective)	Inspection Level or Code	First Sample	Combined Sample	Sym.	Min	Max	Units
ACCEPTAN	CE LIFE TESTS (cont'd.)									
4.11.4	Life—test end points (intermittent) (500 hours)	(See note 20) Inoperatives (See note 21) Total grid current Heater Current Change in transcon— ductance (1) of in— dividual tubes Transconductance (2) Heater—cathode Ieakage Ehk=+100 Vdc			1 1 1	3 3 3 3	Δ_{Ef}^{Sm}	0 142	-0.7 162 20	μΑ mA %
		Ehk=-100 Vdc Insulation of electrodes E(g-all)=-100V E(p-all)=-300 V			1	3	{Ihk Ihk R Avg∆,Sm	250 250	 15	μAdc μAdc Meg. Meg. %
		Transconductance(1) average change Total defectives	•••		3	6	Avg/A _t Sm			%



			AQL (Percent Defective)	Inspection		le Defects tracteristic		LI	MITS	
Par. No.	Test	Conditions		Level or Code	First Sample	Combined Sample	Sym.	Min.	Max.	Units
ACCEPTA	NCE LIFE TESTS (cont'd.)									
4.11.4	Life—test end points (intermittent) (1000 hours)	(See note 20) Inoperatives (see note 21) Total grid current]	3	····		-0.7	μAdc
		Heater current			l i	3 3	iř	142	164	mA
		Change in transcon— ductance (1) of in— dividual tubes		•••	i	3	$\ddot{\Delta}_{\!\scriptscriptstyle{f f}}$ Sm		25	%
		Transconductance (2) Heater—cathode	•	•••	1	3	Δ_{Ef}^{Sm}		20	%
		leakage Ehk=+100 Vdc Ehk=-100 Vdc Insulation of	•••	•••	1	3	∫lhk [lhk		7 7	μAdc μAdc
		electrodes E(g-all)=-100 Vdc E(p-all)=-300 Vdc Total defectives			1 4	3	R R	100		Meg Meg
4.11.8	Cathode interface life test	Ef=6.9 V; heaters in parallel; other electrodes disconnected (see note 22)					t	500		hr
4.11.4	Life—test end points	Ef=5.7±0.05 Vdc, heaters in parallel, Eb=135 Vdc; Ec/lb=2.0 mAdc (see notes 23 and 24)	•••	•••	1	3	Ri	•••	50	ohm
4.9.18	Container drop (see note 25)	(d) Package group 1, container size B								

- Note 1: The sequence of tests listed hereon is the suggested order in which the tests should be conducted.
- Note 2: Variables sampling procedure (see 4.1.1.7).
- Note 3: All tests listed hereon shall be performed during qualification; however, these three tests are normally performed qualification inspection only.
- Note 4: Tie 1k to 2k; 1g to 2g; and 1p to 2p.
- Note 5: The AQL for the combined defectives for attributes in measurements acceptance tests, part 1, excluding inoperatives and mechanical shall be 1 percent.
- Note 6: Test each unit separately.
- Note 7: Prior to this test, tubes shall be preheated a minimum of 5 minutes with all sections operating at the conditions indicated below. The 3-minute test is not permitted. Test at specified conditions within 3 seconds after preheating. Grid emission shall be the last test performed on the sample selected for the grid emission test.

Ef	Ec1	Vdc	Rk/k	Rg/g
V	Vdc	Eb	ohms	Meg
15.0	0	250	200	0.5

Note 8: In addition to the rejection criteria of 4.10.3.1, the output shall be read on a VU meter using a rejection limit of 5 VU. Five VU is the meter deflection obtained with a steady state output of 3 mW from the amplifier.



NOTES (con't)

- Note 9: The rejection level shall be set at the VU meter reading obtained during calibration.
- Note 10: The grid is driven with a pulse voltage as follows: egk=+30 v; prr=1000; tp=10 μs; tr <1 μs; tf <1 μs (egk shall be defined as the instantaneous peak voltage between the grid and the negative end of the cathode resistor). Peak cathode current shall be measured by means of a high impedance oscilloscope, or equivalent, device connected across a cathode resistor of 1.0 ohm. Preheat at Ef=12.6 V for 5 minutes; no other voltages applied.
- Note 11: This test shall be conducted on the initial lot and thereafter on a lot approximately every 30 days. When one lot has passed, the 30—day rule shall apply. In the event of lot failure, the lot shall be rejected and the succeeding lots shall be subjected to this test until one lot passes. Standard MIL—STD—105, sample size code letter F, shall apply.
- Note 12: Destructive tests. Tubes subjected to the following destructive tests shall not be delivered on the contract or order:
 - 4.9.20.5 Shock test
 - 4.9.20.6 Fatigue test
 - 4.11.7 Heater-cycling life test
 - 4.11.5 Intermittent life-test operation
 - 4.11.8 Cathode interface life test
- Note 13: A grid resistor of 0.1 Meg shall be added to each section; however, this resistor shall not be used when a thyratron—type short indicator is employed.
- Note 14: The no-load to steady state full load regulation of the heater voltage supply shall be not more than 3.0 percent. This test shall be made on a iot-by-lot basis. A failure or defect shall consist of an open heater, open cathode circuit, heater-cathode short, or heater-cathode leakage current in excess of the specified heater-cycling life-test end-point limit.
- Note 15: Stability life test. See 20.2.5.1 of Appendix C.
- Note 16: Survival—rate life test. See 20.2.5.2 to 20.2.5.2.4, inclusive, of Appendix C.
- Note 17: For survival-rate life test, the equivalent stability life-test conditions shall be so specified in 20.2.5.2.5 of Appendix C.
- Note 18: Intermittent life tests. See 20.2.5.3 of Appendix C.
- Note 19: Envelope temperature is defined as the highest temperature indicated when using a thermocouple of No. 40 B & S or smaller diameter elements welded to a ring of 0.025—inch diameter phosphor bronze in contact with the envelope. The envelope temperature requirement will be satisfied if a tube having bogie plate current (±5 percent) under normal test conditions, is determined to operate at or above the minimum specified temperature in any position of the life—test rack.
- Note 20: Order for evaluation of life-test defects. See 4.11.3.1.2.
- Note 21: An inoperative as referenced in life test is defined as a tube having one or more of the following defects: Discontinuity (see 4.7.1 except tube shall not be tapped), permanent short (see 4.7.2 except tube shall not be tapped), air leaks. (See 4.7.6)
- Note 22: The cathode interface life—test sample shall consist of 20 tubes, and not more than one tube failure shall be permitted. In the event of rejection of the first sample due to failure of more than one tube, a second sample of 40 tubes shall be selected from the lot.

 Acceptance shall then be based on the combined first and second samples. The total tube failures from the combined first and second samples shall not exceed three. A life—test defect is defined as a failure to meet the life—test end—point limits as specified on the tube specification sheet. The cathode interface life—test sample shall be read at zero hours and 500 hours (plus 48 hours, minus 24 hours).



NOTES: (cont'd.)

Note 23: Preheat approximately 5 minutes prior to testing, using either Ef=11.4 V (heaters in series) or Ef=5.7 V (heaters in parallel), other electrodes disconnected. No other test shall be made from the start of the cathode interface life test until after the measurement of the end point characteristic, following completion of the indicated minimum number of life—test hours.

Note 24: The value of interface resistance shall be measured in the standard test circuit. Drawing 248-JAN. As an alternative, a test method known to correlate with the method and conditions specified in this specification sheet may be utilized.

Note 25: Not required for qualification.

